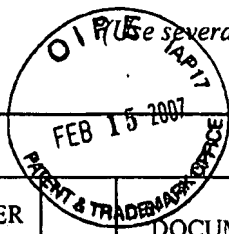


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	APPLICANT Akihisa KOBAYASHI, et al.	
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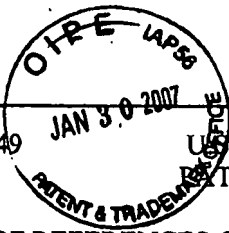
FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY		<u>TRANSLATION</u> YES NO PART.		
/DB/	AG	EP 1 388 404 B1	February 11, 2004	European	Corresponds to DE 101 43 013 A1		X
/DB/	AH	DE 101 43 013 A 1	March 20, 2003	German		X	
/DB/	AI	GB 2 342 190 A	April 5, 2000	United Kingdom	Corresponds to DE 198 44 744 C 1	X	
/DB/	AJ	DE 198 44 744 C 1	September 29, 1998	German		X	
/DB/	AK	WO 02055886	August 14, 2002	PCT	Corresponds to DE 102 01 183 A 1		X
/DB/	AL	DE 102 01 183 A 1	August 14, 2002	German		X	
	AM						

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AL	
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	APPLICANT Akihisa KOBAYASHI, et al.	
	FILING DATE December 8, 2005	GROUP 1764

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EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
/DB/	AA	2003/0090019 A1	May 15, 2003	Amano			
	AB						
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	AE						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY		<u>TRANSLATION</u> YES NO PART.		
/DB/	AG	2003/0040168	May 22, 2003	Korean	Corresponds to US 2003/0090019 A1			
	AH							
	AI							
	AJ							
	AK							

OTHER REFERENCES *(Including Author, Title, Date, Pertinent Pages, Etc.)*

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EXAMINER /Dimple Bodawala/	DATE CONSIDERED 06/27/2007
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Sheet 1 of 1

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		FILING DATE December 8, 2005	GROUP Not Yet Assigned

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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO PART.		
/DB/	AG	2003-145600	05/2003	JAPAN					
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/DB/	AI	5-92462	04/1993	JAPAN					
/DB/	AJ	60-56422	04/1985	JAPAN					
	AK								

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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